

**Search Notes****Application/Control No.**

10/698,222

**Examiner**

Toan M. Le

**Applicant(s)/Patent under Reexamination**

SHI ET AL.

**Art Unit**

2863

**SEARCHED**

| Class | Subclass | Date      | Examiner |
|-------|----------|-----------|----------|
| 702   | 57       | 3/24/2005 | TL       |
| 324   | 671      | 3/24/2005 | TL       |
| 324   | 455      | 3/24/2005 | TL       |
| 438   | 17       | 3/24/2005 | TL       |
| 438   | 16       | 3/24/2005 | TL       |
| 324   | 765      | 3/24/2005 | TL       |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|   | DATE      | EXMR |
|---|-----------|------|
| Contactless Insulating Dielectric Film Characterization   | 3/23/2005 | TL   |
| Substrate, Dielectric Film, Voltage, Kelvin Probe         | 3/23/2005 | TL   |
| Substrate, Film, Thickness, Nitrogen, Charge, Non-Contact | 3/18/2005 | TL   |
| East, Web, and NPL search                                 |           |      |
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**INTERFERENCE SEARCHED**

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